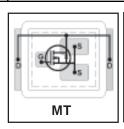
# International Rectifier

# IRF6601/IRF6601TR1

HEXFET® Power MOSFET

- Application Specific MOSFETs
- Ideal for CPU Core DC-DC Converters
- Low Conduction Losses
- Low Switching Losses
- Low Profile (<0.7 mm)
- Dual Sided Cooling Compatible
- Compatible with exisiting Surface Mount Techniques

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	Qg
20V	$3.8$ m $\Omega$ @ $V_{GS} = 10V$	30nC
	$5.0 \text{m}\Omega @V_{GS} = 4.5 \text{V}$	





Applicable DirectFET Package/Layout Pad (see p.9, 10 for details)

_								
	SQ	SX	ST	MQ	MX	MT		

#### **Description**

The IRF6601 combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has the footprint of an SO-8 and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems, IM-PROVING previous best thermal resistance by 80%.

The IRF6601 balances both low resistance and low charge along with ultra low package inductance to reduce both conduction and switching losses. The reduced total losses make this product ideal for high efficiency DC-DC converters that power the latest generation of processors operating at higher frequencies. The IRF6601 has been optimized for parameters that are critical in synchronous buck converters including Rds(on), gate charge and Cdv/dt-induced turn on immunity. The IRF6601 offers particularly low Rds(on) and high Cdv/dt immunity for synchronous FET applications.

#### Absolute Maximum Ratings

	Parameter	Max.	Units
V <sub>DS</sub>	Drain-to-Source Voltage	20	V
V <sub>GS</sub>	Gate-to-Source Voltage	±20	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	85	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	26	А
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	20	
I <sub>DM</sub>	Pulsed Drain Current ①	200	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ©	3.6	
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation ©	2.3	W
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	42	
	Linear Derating Factor	0.029	W/°C
T <sub>J</sub>	Operating Junction and	-40 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		

### Thermal Resistance

	Parameter	Тур.	Max.	Units				
$R_{\theta JA}$	Junction-to-Ambient @		35					
$R_{\theta JA}$	Junction-to-Ambient S	12.5		1				
$R_{\theta JA}$	Junction-to-Ambient ®	20		°C/W				
$R_{\theta JC}$	Junction-to-Case ⑦		3.0	1				
R <sub>0J-PCB</sub>	Junction-to-PCB Mounted	1.0		1				

Notes ① through ⑦ are on page 11

### Static @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	20			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta \mathrm{BV}_{\mathrm{DSS}}/\Delta \mathrm{T}_{\mathrm{J}}$	Breakdown Voltage Temp. Coefficient		19		mV/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		3.2	3.8	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 26A ③
			4.4	5.0		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 21A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.0	1.62	2.2	V	$V_{DS} = V_{GS}, I_{D} = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient		-4.6		mV/°C	
				100		$V_{DS} = 20V, V_{GS} = 0V$
$I_{DSS}$	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 16V, V_{GS} = 0V$
				100	Ī	$V_{DS} = 16V, V_{GS} = 0V, T_{J} = 70^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100	Ī	$V_{GS} = -20V$
gfs	Forward Transconductance	50			S	$V_{DS} = 10V, I_D = 21A$
$Q_g$	Total Gate Charge		30	45		
Q <sub>gs1</sub>	Pre-Vth Gate-to-Source Charge		5.4		ĺ	$V_{DS} = 10V$
Q <sub>gs2</sub>	Post-Vth Gate-to-Source Charge		2.9		nC	$V_{GS} = 4.5V$
$Q_{gd}$	Gate-to-Drain Charge		12		ĺ	I <sub>D</sub> = 16A
$Q_{godr}$	Gate Charge Overdrive		9.2		ĺ	See Fig. 16
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		15	_	Ī	
Q <sub>oss</sub>	Output Charge		48		nC	$V_{DS} = 16V, V_{GS} = 0V$
R <sub>G</sub>	Gate Resistance		1.9	3.2	Ω	
t <sub>d(on)</sub>	Turn-On Delay Time		61	_		V <sub>DD</sub> = 15V, V <sub>GS</sub> = 4.5V ③
t <sub>r</sub>	Rise Time		21		Ī	I <sub>D</sub> = 21A
t <sub>d(off)</sub>	Turn-Off Delay Time		28		ns	Clamped Inductive Load
t <sub>f</sub>	Fall Time		22		1	
C <sub>iss</sub>	Input Capacitance		3440			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		2430		рF	V <sub>DS</sub> = 15V
C <sub>rss</sub>	Reverse Transfer Capacitance		380		1	f = 1.0 MHz

### **Avalanche Characteristics**

	Parameter	Тур.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>②</sup>		65	mJ
I <sub>AR</sub>	Avalanche Current ①		21	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①		0.36	mJ

### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			26		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			200		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage		0.83	1.2	V	$T_J = 25$ °C, $I_S = 21A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		60	90	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 21A
Q <sub>rr</sub>	Reverse Recovery Charge		94	140	nC	di/dt = 100A/µs ③

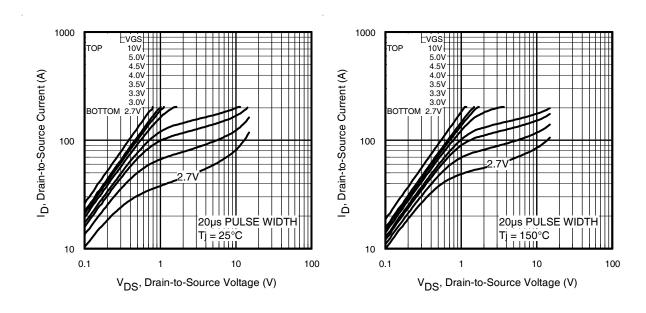


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

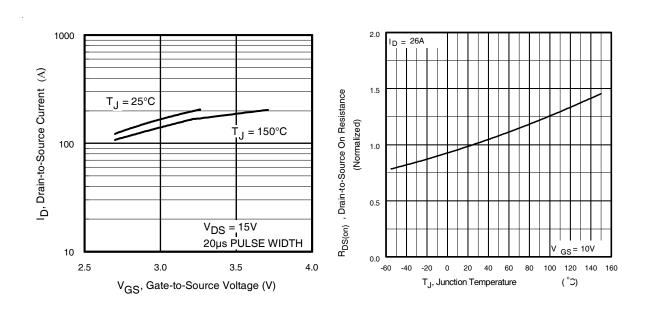
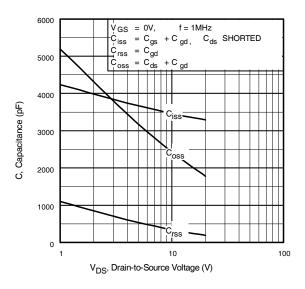


Fig 3. Typical Transfer Characteristics

**Fig 4.** Normalized On-Resistance Vs. Temperature



12.0 I<sub>D</sub>= 16A 10.0 V<sub>GS</sub>, Gate-to-Source Voltage (V) V<sub>DS</sub>= 16V  $V_{DS} = 10V$ 8.0 6.0 4.0 2.0 0.0 0 10 20 30 40 Q<sub>G</sub> Total Gate Charge (nC)

**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

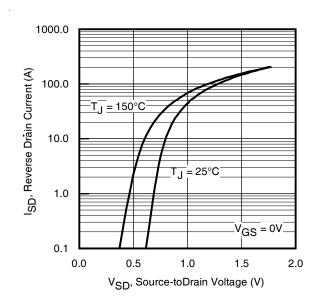


Fig 7. Typical Source-Drain Diode Forward Voltage

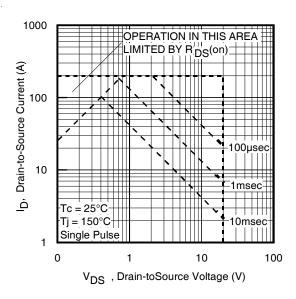
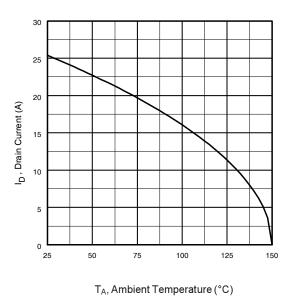


Fig 8. Maximum Safe Operating Area



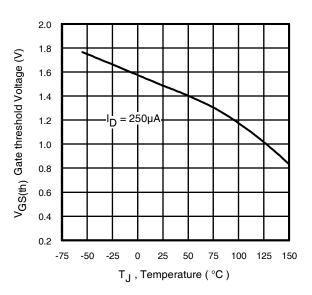


Fig 9. Maximum Drain Current Vs. Ambient Temperature

Fig 10. Threshold Voltage Vs. Temperature

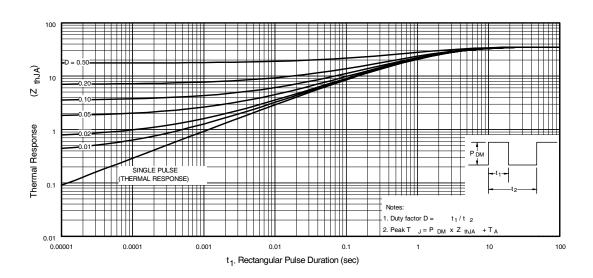


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

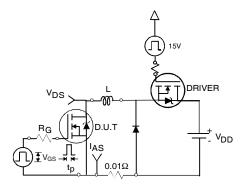


Fig 12a. Unclamped Inductive Test Circuit

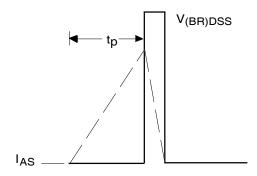


Fig 12b. Unclamped Inductive Waveforms

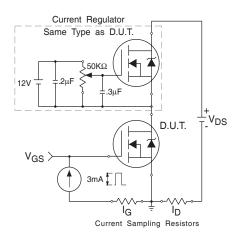
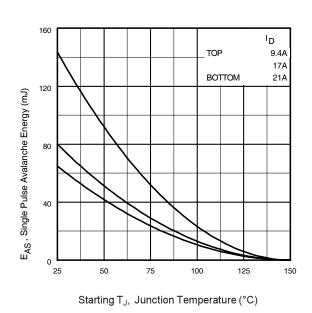


Fig 13. Gate Charge Test Circuit



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

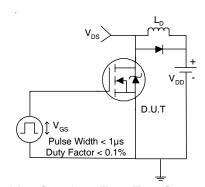


Fig 14a. Switching Time Test Circuit

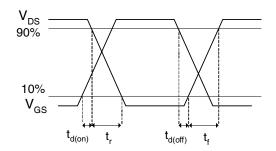


Fig 14b. Switching Time Waveforms

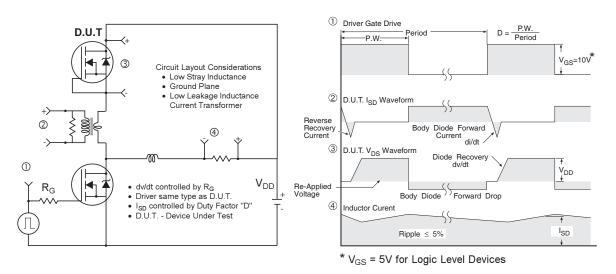


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

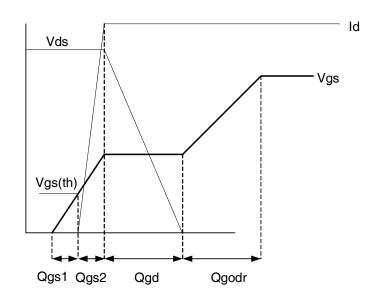


Fig 16. Gate Charge Waveform

#### Power MOSFET Selection for Non-Isolated DC/DC Converters

#### **Control FET**

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the  $R_{\rm ds(on)}$  of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms  $Q_{gs2}$  and  $Q_{oss}$  which are new to Power MOSFET data sheets.

 $Q_{gs2}$  is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements,  $Q_{gs1}$  and  $Q_{gs2}$ , can be seen from Fig 16.

 $Q_{gs2}$  indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to  $I_{dmax}$  at which time the drain voltage begins to change. Minimizing  $Q_{gs2}$  is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$  is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how  $\rm Q_{oss}$  is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's  $\rm C_{ds}$  and  $\rm C_{dg}$  when multiplied by the power supply input buss voltage.

#### Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

\*dissipated primarily in Q1.

For the synchronous MOSFET Q2,  $R_{\rm ds(on)}$  is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge  $Q_{oss}$  and reverse recovery charge  $Q_{rr}$  both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and V  $_{\rm in}$ . As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of Q  $_{\rm gd}/Q_{\rm gs1}$  must be minimized to reduce the potential for Cdv/dt turn on.

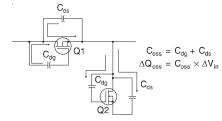
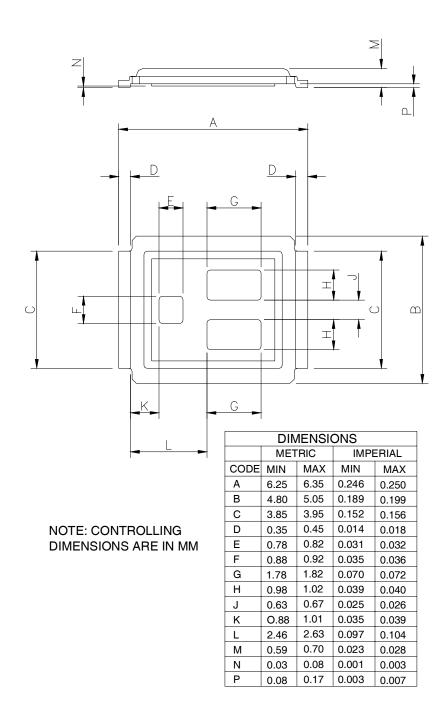


Figure A: Q Characteristic

### DirectFET™ Outline Dimension, MT Outline

(Medium Size Can, T-Designation)

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.

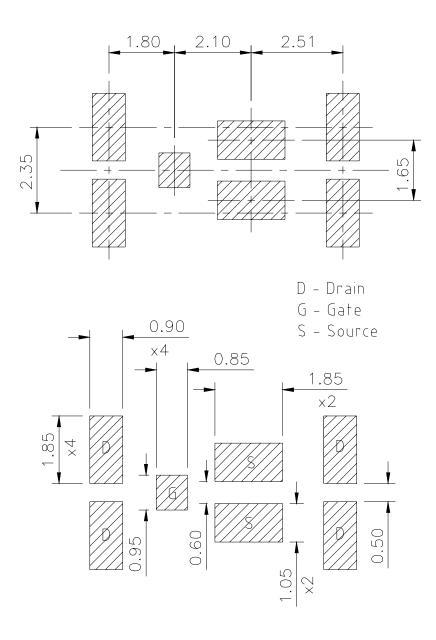


### DirectFET™ Board Footprint, MT Outline

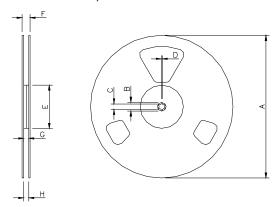
(Medium Size Can, T-Designation)

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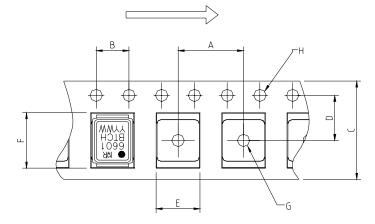
# DirectFET™ Tape and Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm Std reel quantity is 4800 parts. (ordered as IRF6601). For 1000 parts on  $7^{\circ}$  reel, order IRF6601TR1

	REEL DIMENSIONS									
S	TANDARI	O OPTION	I (QTY 48	00)	TR	1 OPTION	(QTY 10	00)		
	ME	TRIC	IMP	ERIAL	ME	TRIC	IMP	ERIAL		
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
Α	330.0	N.C	12.992	N.C	177.77	N.C	6.9	N.C		
В	20.2	N.C	0.795	N.C	19.06	N.C	0.75	N.C		
С	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50		
D	1.5	N.C	0.059	N.C	1.5	N.C	0.059	N.C		
Е	100.0	N.C	3.937	N.C	58.72	N.C	2.31	N.C		
F	N.C	18.4	N.C	0.724	N.C	13.50	N.C	0.53		
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C		
Н	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C		

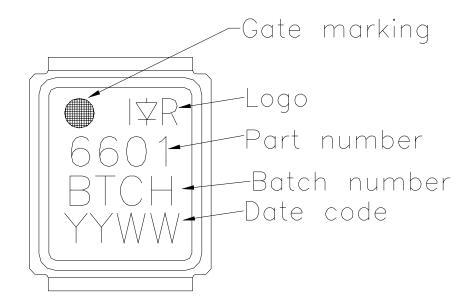
Loaded Tape Feed Direction



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS									
	ME	TRIC	IMPERIAL						
CODE	MIN	MAX	MIN	MAX					
Α	7.90	8.10	0.311	0.319					
В	3.90	4.10	0.154	0,161					
С	11.90	12.30	0.469	0.484					
D	5,45	5.55	0.215	0.219					
Ε	5.10	5.30	0.201	0.209					
F	6.50	6.70	0.256	0.264					
G	1,50	N.C	0.059	N.C					
Н	1,50	1.60	0.059	0.063					

### DirectFET™ Part Marking



#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $\label{eq:tarting} \begin{array}{ll} \text{ Starting T}_J = 25^{\circ}\text{C}, \ L = 0.24\text{mH}, \\ \text{R}_G = 25\Omega, \ \text{I}_{AS} = 20\text{A}. \end{array}$
- ③ Pulse width  $\leq$  400 $\mu$ s; duty cycle  $\leq$  2%.
- Surface mounted on 1 in. square Cu board.
- ⑤ Used double sided cooling, mounting pad.
- ⑥ Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- T<sub>C</sub> measured with thermal couple mounted to top (Drain) of part.

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market.

Qualification Standards can be found on IR's Web site.



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TAC Fax: (310) 252-7903

Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>